

Search Notes

Application/Control No.

10/766,646

Examiner

Eric B. Chen

Applicant(s)/Patent under
Reexamination

LEE, HEON

Art Unit

1765

SEARCHED

| Class | Subclass | Date | Examiner |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|---|-----------|------|
| Inventor search (PALM) | 9/13/2005 | EC |
| EAST (all databases) - see search history printout | 9/14/2005 | EC |
| 216/2, 11-13, 33-36, 44, 52 54, 67, 79, 81, 88-91, 96; 264/320; 249/115, 118, 114.1 (text search only) (consulted A. Alanko, B. Tran) | 9/15/2005 | EC |
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